3	searcr	n Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/540,556	DUBEY ET AL.	
Examiner	Art Unit	
Brian J. Davis	1621	

SEARCHED			
Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOT (INCLUDING SEARCH)
·	DATE	EXMR
Structure, key word and registry number searches on STN (see search history printout)	1/19/2008	BJD
Inventor name searches on PALM	1/19/2008	BJD
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